## Search Notes



Application/Control No.	Applicant(s)/Patent Under Reexamination
10585052	YEO ET AL.
Examiner	Art Unit
David Ton	2117

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Class	Subclass	Date	Examiner
370	329	5/10/09	DT
370	278	5/10/09	DT
370	236	5/10/09	DT
370	235	5/10/09	DT
714	248	7/18/09	DT
714	249	7/18/09	DT
370	394	7/18/09	DT

SEARCH NOTES				
Search Notes	Date	Examiner		
EAST, DERWENT, JPO, IEEE searches	5/10/09	DT		
EAST, DERWENT, JPO searches	7/18/09	DT		

INTERFERENCE SEARCH					
Class		Subclass	Date	Examiner	
714	748		7/18/09	DT	
370	394		7/18/09	DT	

/David Ton/ Primary Examiner.Art Unit 2117	/David Ton/ Primary Examiner.Art Unit 2117	
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